Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/710,288	BEYER ET AL.	
Examiner	Art Unit .	
Cong-Lac Huynh	2178	

SEARCHED					
Class	Subclass	Date	Examiner		
715	500	10/22/2007	CLH		
	513	10/22/2007	CLH		
	514	10/22/2007	CLH		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
715	514	10/22/2007	CLH	
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Interference Search History Printout		10/25/2007	CLH	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
East (USPAT, USPGPUB, JPO, EPO, Derwent)	10/22/2007	CLH
ACM	10/22/2007	CLH
Google	10/25/2007	CLH
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